

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10607929	SPLIER ET AL.
	Examiner	Art Unit
	LE NGUYEN	2174

SEARCHED

Class	Subclass	Date	Examiner
715	827	2/1/084	lvn

SEARCH NOTES

Search Notes	Date	Examiner
EPO, JPO; ACM library, IEEE Xplore; US-PGPUB, USPAT: 345/168,169,172,173; 715/773,827,865	2/6/08	lvn
consulted w/Ba Huynh	2/7/08	lvn

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
715	827	2/1/084	lvn